



## *ISC Audits & Reviews SC Summary August 2016*

<b>Doc. #</b>	<b>Title</b>	<b>Result</b>
<b>3440C;</b>	<b>New Standard: Test Method For Pressure Transducers In Gas Delivery Systems;</b>	Passed
<b>5016;</b>	<b>Line Item Revision to SEMI HB3-1113, Mechanical Interface Specification for 150 mm HB-LED Load Port</b>	
5016-LI1;	Correct the title of this Standard from “Mechanical Interface Specification for 150 mm HB-LED Load Port” to “Specification for the Mechanical Interface for 150 mm HB-LED Load Port”;	Passed
<b>5244B;</b>	<b>Revision of SEMI F21-1102, Classification of Airborne Molecular Contaminant Levels in Clean Environments;</b>	Passed
<b>5556B;</b>	<b>Line Item Revisions to SEMI S2-0712, Environmental, Health, and Safety Guideline for Semiconductor Manufacturing Equipment. Delayed Revisions Related to Section 19 Seismic Protection</b>	
5556B-LI1	Revision to §19 “Seismic Protection”	Passed
<b>5713A;</b>	<b>New Standard: Specification For Glass Base Material For Semiconductor Packaging;</b>	Passed
<b>5744A;</b>	<b>Line Item Revision to SEMI M49-0613 - Guide for Specifying Geometry Measurement Systems for Silicon Wafers for the 130 nm to 16 nm Technology Generations (Re: to clarify and better define exclusion windows)</b>	
5744A-LI1;	Add more specific description for exclusion windows at section 5.5.22, and rewrite section 3.4 at table 3 and table 4. Also maintain update in the table 2.;	Passed
<b>5817A;</b>	<b>Revision to SEMI E72-0600 (Reapproved 0305), Specification and Guide for 300 mm Equipment Footprint, Height, and Weight with title change to: Specification and Guide for Equipment Footprint, Height, and Weight;</b>	Passed
<b>5821C</b>	<b>New Standard: Specification for Energy Savings Mode Communication between Semiconductor Equipment and Sub-Systems</b>	Passed
<b>5889;</b>	<b>New Standard: Test Method on Cell Level for Potential-Induced Degradation Susceptibility of Solar Cells and Module Encapsulation Materials;</b>	Passed
<b>5912A</b>	<b>Line Item Revisions to: SEMI E142.1 -0211, SEMI E142.2-0211, SEMI E142.3-0211, To correct nonconforming titles</b>	
5912A-LI1;	Correct Nonconforming Title of SEMI E142.1-0211;	Passed

Doc. #	Title	Result
5912A-LI2;	Correct Nonconforming Title of SEMI E142.2-0211;	Passed
5912A-LI3;	Correct Nonconforming Title of SEMI E142.3-0211;	Passed
<b>5917</b>	<b>Line Item Revisions to SEMI S8, Safety Guideline for Ergonomics Engineering of Semiconductor Manufacturing Equipment. Addition of reference to a manual material-handling guide in SEMI-S8, Appendix 2, Lifting, Strength, and Materials Handling</b>	
5917-LI1;	Add a Definition for “hand-object coupling point” in the Terminology Section;	Passed
5917-LI2;	Add a reference to SEMATECH ISMI Manual Material Handling Application Guide ;	Passed
<b>5944A;</b>	<b>Revision to SEMI F63-0213, Guide for Ultrapure Water Used in Semiconductor Processing;</b>	Passed
<b>5947A;</b>	<b>Revision to SEMI S23, Guide for Conservation of Energy, Utilities and Materials Used by Semiconductor Manufacturing Equipment. New Scope and Small Changes;</b>	Passed
<b>5960A;</b>	<b>Revision of SEMI PV21-1011 Guide for Silane (SiH4), Used in Photovoltaic Applications;</b>	Passed
<b>5961A;</b>	<b>Revision of SEMI PV24-1011 Guide for Ammonia (NH3) in Cylinders, Used in Photovoltaic Applications;</b>	Passed
<b>5962A;</b>	<b>Revision of SEMI PV26-1011 Guide for Hydrogen Selenide (H2Se) in Cylinders, Used in Photovoltaic Applications;</b>	Passed
<b>5963A</b>	<b>Line Item Revision To SEMI F62-0701 (Reapproved 1111) Test Method For Determining Mass Flow Controller Performance Characteristics From Ambient And Gas Temperature Effects</b>	
5963A-LI1;	Line item change to modify terminology in Section 5.1;	Passed
5963A-LI2;	Line item change to modify Section 15.1 as shown ;	Passed
<b>5970</b>	<b>Line Item Revisions to SEMI S14, Safety Guidelines for Fire Risk Assessment and Mitigation for Semiconductor Manufacturing Equipment</b>	
<b>5970-LI1;</b>	<b>Changes to Terminology to Align with SEMI S10. ;</b>	<b>Failed</b>
<b>5989;</b>	<b>Revision of SEMI M62-0515, Specifications for Silicon Epitaxial Wafers;</b>	Passed
<b>5990;</b>	<b>Revision of SEMI MF1811-0116 Guide For Estimating The Power Spectral Density Function And Related Finish Parameters From Surface Profile Data;</b>	Passed

Doc. #	Title	Result
5992;	<b>Revision to SEMI F41-0699, Guide for Qualification of a Bulk Chemical Distribution System Used in Semiconductor Processing;</b>	Passed
5993	<b>Line Item Revision of SEMI M1-0416, Specification for Polished Single Crystal Silicon Wafers</b>	
5993-LI1;	Clarify the heading and intent of section 7;	Passed
5994	<b>Line Item Revision to SEMI M50, Test Methods for Determining Capture Rate and False Count Rate for Surface Scanning Inspection Systems by the Overlay Method (Fix title for conformance)</b>	
5994-LI1;	Correct the title of this standard from "TEST METHODS" to "TEST METHOD" and modify section 1.2 and 2.1 as shown.;	Passed
5998	<b>Line Item Revision to SEMI C54-1103 (Reapproved 0211), Specifications and Guidelines for Oxygen</b>	
5998-LI1;	Correct the title of this Standard from "Specifications and Guidelines for Oxygen" to "Specification for Oxygen";	Passed
5999	<b>Line Item Revision to SEMI C56-0305 (Reapproved 0211), Specifications and Guidelines for Dichlorosilane (SiH<sub>2</sub>Cl<sub>2</sub>)</b>	
5999-LI1;	Correct the title of this Standard from "Specifications and Guidelines for Dichlorosilane (SiH <sub>2</sub> Cl <sub>2</sub> )" to "Specification for Dichlorosilane";	Passed
6001	<b>Line Item Revision to SEMI C58-1213, Specifications for Hydrogen</b>	
6001-LI1;	Correct the title of this Standard from "Specifications for Hydrogen" to "Specification for Hydrogen";	Passed
6004	<b>Line Item Revision to SEMI C70-0611, Specifications for Tungsten Hexafluoride (WF<sub>6</sub>)</b>	
6004-LI1;	Correct the title of this Standard from "Specifications for Tungsten Hexafluoride (WF <sub>6</sub> )" to "Specification for Tungsten Hexafluoride";	Passed
6010;	<b>Reapproval of SEMI D34-0710, Test Method for FPD Polarizing Films;</b>	Passed
6011;	<b>Reapproval of SEMI D38-0211, Guide for Quality Area of LCD Masks;</b>	Passed
6012;	<b>Reapproval of SEMI D39-0704 (Reapproved 0710), Specification for Markers on FPD Polarizing;</b>	Passed
6013;	<b>Reapproval of SEMI D6-0211, Specification for Liquid Crystal Display (LCD) Mask Substrates;</b>	Passed
6017	<b>Line-item Revision to SEMI E33-1012 Guide for Semiconductor Manufacturing Equipment Electromagnetic Compatibility (EMC)</b>	
6017-LI1;	To update the referenced EC Directive in section 4.2 and Related Information 3.;	Passed
6019	<b>Line item revision of SEMI M1-0416, Specification for Polished Single Crystal Silicon Wafers</b>	
6019-LI1;	Correct and update Figure 3.;	Passed
6019-LI2;	Remove redundant notes from the caption of Figure 7, and delete the term "outer" before "FQA boundary.";	Passed



Doc. #	Title	Result
6019-LI4;	Add "and bow" to Note 13.;	Passed
6019-LI5;	Add "and 450" to ¶R3-9.5 and correct the reference to ¶R3-9.4.;	Passed
<b>6020</b>	<b>Line Item Revision to SEMI E30.1-0309: Inspection and Review Specific Equipment Model (ISEM) to correct nonconforming title</b>	
6020-LI1;	Correct nonconforming title;	Passed
<b>6021</b>	<b>Line Item Revision to SEMI E123-0703 (Reapproved 1109) - Standard for Handler Equipment Specific Equipment Model (HSEM) to correct nonconforming title</b>	
6021-LI1;	Correct nonconforming title;	Passed
<b>6022</b>	<b>Line Item Revision to SEMI E138-0709 - XML Semiconductor Common Components to correct nonconforming title</b>	
6022-LI1;	Correct nonconforming title;	Passed
<b>6023</b>	<b>Line Item Revision to SEMI E122-0703 (Reapproved 1109) - Standard for Tester Equipment Specific Equipment Model (TSEM) to correct nonconforming title</b>	
6023-LI1;	Correct nonconforming title;	Passed
<b>6024</b>	<b>Reapproval of SEMI E30.5-0302 (Reapproved 0308) - Specification for Metrology Specific Equipment Model (MSEM);</b>	Passed
<b>6025;</b>	<b>Reapproval of SEMI E142-0211 - Specification for Substrate Mapping;</b>	Passed
<b>Addition of RI</b>	<b>Add Related Information (RI) to SEMI E111, References to SEMI E19, E112, and E117.</b>	Passed

Line Item (LI)

Doc. 5970-Line Item 1 failed. All other documents passed and will be forwarded to Standards Publications for final processing.

For more information, please contact the SEMI Standards Engineer/Coordinator (<http://www.semi.org/en/standards/contacts>) nearest you.

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August 30, 2016